

**Search Notes**

Application/Control No.

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Examiner

Cong-Lac Huynh

Applicant(s)/Patent under  
Reexamination

BEYER ET AL.

Art Unit

2178

**SEARCHED**

Class	Subclass	Date	Examiner
715	500	10/22/2007	CLH
	513	10/22/2007	CLH
	514	10/22/2007	CLH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
715	514	10/22/2007	CLH
Interference Search History Printout		10/25/2007	CLH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (USPAT, USPGPUB, JPO, EPO, Derwent)	10/22/2007	CLH
ACM	10/22/2007	CLH
Google	10/25/2007	CLH